



Fluktuacje w Rozpraszaniu Promieniowania X i Neutronów

Indeks: **831106** Producent: **Springer** Kod producenta: **biography**

Cena: **463.92 zł**

Opis

Diffuse Scattering of X-Rays and Neutrons by Fluctuations

Producent: Springer

- **temat:** Electronics engineering, Laser physics, Testing of materials, Science / Physics / Crystallography, Science / Physics / Optics & Light, Science/Physics - Crystallography, Science/Physics - Optics & Light, TECHNOLOGY & ENGINEERING / Electronics / General, TECHNOLOGY & ENGINEERING / Optics, Technology & Engineering / Lasers & Photonics, Technology & Engineering/Electronics - General, Technology & Engineering/Lasers & Photonics, Technology & Engineering/Optics, ANF: Technology, Crystallography, Crystallography and Scattering Methods, Electronics, Electronics - General, Electronics and Microelectronics, Instrumentation, Electronics engineering, Elektrizität, Magnetismus, Optik, Elektronik, Elektronik, Elektrotechnik, Nachrichtentechnik, General, Germany, HC, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover, Hardcover, Softcover / Technik/Maschinenbau, Fertigungstechnik, Laser, Laser physics, Laserphysik, Lasers & Photonics, Maschinenbau, Fertigungstechnik, Neutron diffraction, Neutron diffraction;X-Ray;defects in crystals;dislocations;point defects;surface and thin films, Non-Fiction, Optics, Optics & Light, Physics, Physics - Crystallography, Physics - Optics & Light, Physik, Astronomie, SCI/TECH, SCIENCE, SCIENCE / Physics / Crystallography, SCIENCE / Physics / Optics & Light, Scholarly/Graduate, Science/Math, Science/Physics - Crystallography, Science/Physics - Optics & Light, TECHNOLOGY & ENGINEERING, TECHNOLOGY & ENGINEERING / Electronics / General, TECHNOLOGY & ENGINEERING / Lasers & Photonics, TECHNOLOGY & ENGINEERING / Optics, Technik, Technology & Engineering/Electronics - General, Technology & Engineering/Lasers & Photonics, Technology & Engineering/Optics, Testing of materials, Verstehen, Werkstoffprüfung, X-RAY CRYSTALLOGRAPHY, X-Ray, defects in crystals, dislocations, neutron diffraction; X-ray; defects in crystals; dislocations; Point defects; surface and thin films, point defects, surface and thin films, Elektronik, Laserphysik, Werkstoffprüfung, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover / Technik/Maschinenbau, Fertigungstechnik
- **wiążący:** paperback
- **język:** english, english, english
- **waga przedmiotu:** 426 grams
- **strony:** 304
- **słowo kluczowe tematu:** Germany, Neutron diffraction, Neutron diffraction; point defects; dislocations; defects in crystals; X-Ray; surface and thin films, Neutron diffraction;X-Ray;defects in crystals;dislocations;point defects;surface and thin films, Non-Fiction, SCI/TECH, Scholarly/Graduate, Science/Math, X-RAY CRYSTALLOGRAPHY, X-Ray, defects in crystals, dislocations, neutron diffraction; X-ray; defects in crystals; dislocations; Point defects; surface and thin films, point defects, surface and thin films
- **marka:** Springer
- **kod unspsc:** 55101500
- **kod podmiotu:** SCI016000, SCI053000, SCI016000, SCI053000, TEC008000, TEC030000, TEC019000, TEC008000, TEC019000, TEC030000, 1643, 1684, 1682, 1682, TJF, PHJL, TGMT, TJF, PHJL, TGMT

- **grupa docelowa:** College/University
- **numer części:** biography
- **kolor:** White
- **waga opakowania przedmiotu:** 0.95 pounds
- **wydanie:** 1996
- **zewnętrznie przypisany identyfikator produktu:** 3642787673, 9783642787676, 09783642787676
- **producent:** Springer
- **autor:** Krivoglaз, Mikhail A. A.
- **gatunek muzyczny:** Testing of materials, Laser physics, Electronics engineering, SCIENCE, Physics, Crystallography, SCIENCE, Physics, Optics & Light, TECHNOLOGY & ENGINEERING, Lasers & Photonics, TECHNOLOGY & ENGINEERING, Electronics, General, HC, Technik, Maschinenbau, Fertigungstechnik, HC, Physik, Astronomie, Elektrizität, Magnetismus, Optik, HC, Technik, Elektronik, Elektrotechnik, Nachrichtentechnik, Testing of materials, Laser physics, Electronics engineering
- **Data publikacji:** 2011-12-16T00:00:01Z
- **cena katalogowa uvp:** 106.99
- **numer wydania:** 1
- **nazwa przedmiotu:** Diffuse Scattering of X-Rays and Neutrons by Fluctuations
- **data premiery:** 2011-12-16T00:00:01Z
- **data uruchomienia strony produktu:** 2012-07-08T01:04:18.879Z

Parametry

Rodzaj	Książka
Wydanie	1
Język	Angielski
Waga	426 g
Ilość stron	304